

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/781,941	ASANO ET AL.		
Examiner	Art Unit		
Jeffrey S. Zweizig	2816		

SEARCHED								
CI	Class Subclass Date		te	Examiner				
3	27	309 310	3/3/2005		JZ			
		314 318						
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		328 333						
		564 565						
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	W = 1							

		SEARCH NOTES (INCLUDING SEARCH STRATEGY)						
		DATE	EXMR					
EAST		3/3/2005	JZ					
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108770	1 or 2		. }					
418697								
6887	3 adj 4							
field adj effect adj transistor								
40309	fet							
65151	6 or 7							
1095 5 and 8		V						
	Hits 107833 2162 108770 418697 6887 45064 40309 65151	Hits Searc 107833 electrostatic 2162 electro adj st 108770 1 or 2 418697 discharge 6887 3 adj 4 45064 field adj effet transistor 40309 fet 65151 6 or 7	#its Search Text 107833 electrostatic 2162 electro adj static 108770 1 or 2 418697 discharge 6887 3 adj 4 45064 field adj effect adj transistor 40309 fet 65151 6 or 7					

INTERFERENCE SEARCHED							
Class	Subclass	Date	Examiner				
7							

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